Remarks:

Reconsideration of the application is requested.

Claims 1-16 remain in the application. Claim 1 has been amended. Claims 5-6, 8, and 14-16 have been withdrawn from consideration.

In the third paragraph on page 2 of the above-identified Office action, claims 1-4 and 10-13 have been rejected as being anticipated by *Quinn* (US 3,801,910) under 35 U.S.C. § 102.

In the first paragraph on page 5 of the Office action, claims 7 and 9 have been rejected as being obvious over *Quinn* in view of *Du Chene et al.* (US 4,982,403) under 35 U.S.C. § 103.

The rejections have been noted and claim 1 has been amended in an effort to even more clearly define the invention of the instant application. Support for the changes is found in the second paragraph on page 4 of the specification.

Before discussing the prior art in detail, it is believed that a brief review of the invention as claimed, would be helpful.

Claim 1 as amended calls for, inter alia:

a plurality of circuit points being not externally accessible, providing various electrical signals of the integrated circuit component to be measured or analyzed; and

at least one connecting contact point externally accessible for ***selectively testing any one of the various electrical signals***, said at least one connecting contact point being connected via routes within the integrated circuit component to said plurality of circuit points being not externally accessible.

Quinn discloses a structure for selectively externally accessing mechanically difficult to access circuit nodes using photo-responsive conductors in an integrated circuit.

Clearly, *Quinn* does not show at least one connecting contact point externally accessible for selectively testing any one of the various internal chip signals, as recited in claim 1 of the instant application. Each externally accessible contact point in *Quinn* only contacts one particular internal circuit point. Therefore, the invention as recited in claim 1 of the instant application is not anticipated by *Quinn*.

It is accordingly believed to be clear that *Quinn* does not show the features of claim 1. Claim 1 is, therefore, believed to be patentable over the art and because claims 2-4, 7, and 9-13 are ultimately dependent on claim 1, they are believed to

be patentable as well. *Du Chene et al.* do not make up for the deficiencies of *Quinn*..

In view of the foregoing, reconsideration and allowance of claims 1-4, 7, and 9-13 are solicited.

Please charge any fees which might be due with respect to Sections 1.16 and 1.17 to the Deposit Account of Lerner and Greenberg, P.A., No. 12-1099.

Respectfully submitted,

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For Applicants

MN:cgm

September 25, 2002

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Version with markings to show changes made:

Claim 1 (amended). An integrated circuit component, comprising:

[a plurality of connecting contact points;]

a plurality of circuit points [that are] being not externally accessible, [and that provide] providing various electrical signals of the integrated circuit component to be measured or analyzed; and

[at least one external test connecting contact point to which the signals to be measured or analyzed can be selectively applied such that the signals can be passed on via routes within the integrated circuit component from said plurality of circuit points that are not externally accessible] at least one connecting contact point externally accessible for selectively testing any one of the various electrical signals, said at least one connecting contact point being connected via routes within the integrated circuit component to said plurality of circuit points being not externally accessible.